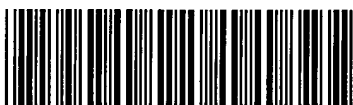


**Search Notes**

Application/Control No.

10/603,667

Examiner

Son M. Tang

Applicant(s)/Patent under  
Reexamination

OHKAWA ET AL.

Art Unit

2612

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
340	572.7	6/21/2006	TANG
↓	572.1	↓	↓
↓	572.4	↓	↓
340/572.6,572.8			

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
340/571-572.8 Text only	6/21/2006	TANG
Benjamin Lee	6/21/2006	TANG